Electronic Supplementary Information (ESI) for

Small Morphology Variations Effects on Plasmonic Nanoparticle

Dimer Hotspots

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Far-field extinction spectra

The calculated far-field extinction spectra of the bridged, creviced, faceted and roughened dimers are plotted in Fig. S1-S4. They are calculated by integrating the time-averaged extinction Poynting vectors S_{ext} (i.e. electromagnetic power flow) over an auxiliary surface A enclosing the dimer, respectively:¹

$$S_{ext} = \frac{1}{2} Re \{ E_{inc} \times H_{sca}^* + E_{sca} \times H_{inc}^* \}$$

$$C_{ext} = \frac{-\iint S_{ext} dA}{|W_{inc}|}$$
(S1)
(S2)

where E_{inc} , E_{sca} , H_{inc} and H_{sca} are the incident and scattered electric and magnetic field respectively. C_{ext} is the extinction cross section, $|W_{inc}| = \frac{1}{2}c\varepsilon_0 E_0^2$ is the power flow per unit area of the incident plane wave, E_0 (set at 1 V/m here) is the modulus of E_{inc} , c is the velocity of light and ε_0 is the permittivity of vacuum.



Figure S1. FEM calculated far-field extinction spectra for the bridge dimers as *b* is increased from 2 to 15nm, corresponding to Fig. 1.



Figure S2. FEM calculated far-field extinction spectra for the creviced dimers as *c* is increased from 5 to 15nm, corresponding to Fig. 3.



Figure S3. FEM calculated far-field extinction spectra for the faceted dimers as f is increased from 2 to 15nm, corresponding to Fig. 5.



Figure S4. FEM calculated far-field extinction spectra for the roughened dimers as r is decreased from 30 to 12 nm, corresponding to Fig. 7.

Reference

1 V. Giannini, A. I. Fernandez-Dominguez, S. C. Heck and S. A. Maier, Chem. Rev., 2011,

111, 3888-3912.